

<b>[ThPM1-06] Raman Metrology 1</b>	
<b>Date / Time</b>	Aug. 30 (Thu.), 2018 / 14:30-16:30
<b>Place</b>	301 (Room E)
<b>Session Chair</b>	Li-Lin Tay (National Research Council Canada, Canada)

**[ThPM1-06-K-1] (Keynote) 14:30-15:00**

**Raman Metrology: A Community Effort towards Standardization and Traceability**

Erlon H. Martins Ferreira

*Inmetro - National Institute of Metrology, Quality and Technology, Brazil*

**[ThPM1-06-I-2] (Invited) 15:00-15:20**

**Comparison of Raman Shifts Obtained under Different Instruments and Conditions**

Nobuyasu Itoh<sup>1,2</sup>, Katsuhiro Shirono<sup>1,2</sup>, and Toshiyuki Fujimoto<sup>1,2</sup>

<sup>1</sup>National Metrology Institute of Japan (NMIJ), Japan, <sup>2</sup>National Institute of Advanced Industrial Science and Technology (AIST), Japan

**[ThPM1-06-I-3] (Invited) 15:20-15:40**

**Raman Standardization for Raman Shift and Intensity Calibration of Spectrometer**

Sungwoon Lee and Hyuksang Kwon

*Korea Research Institute of Standards and Science (KRISS), Korea*

**[ThPM1-06-I-4] (Invited) 15:40-16:00**

**A Novel Approach for Accurate Tip-Enhanced Raman Spectroscopy (TERS) Enhancement Factor Quantification**

Alessio Sacco<sup>1,2</sup>, Chiara Portesi<sup>1</sup>, Luisa Mandrile<sup>1</sup>, Andrea Mario Giovannozzi<sup>1</sup>, and Andrea Mario Rossi<sup>1</sup>

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